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Application/Control No.	Applicant(s)/Patent under Reexamination
10/619,046	HAN ET AL.
Examiner	Art Unit
Khai M. Nguyen	2617

SEARCHED			
Class	Subclass	Date	Examiner
455	444 443 442 441 440 436	3/18/2006	KN

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
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East (see attached)	3/18/2006	kn
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